Silicon Labs - EFM32GG11B420F2048IL112-AR Datasheet

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, IrDA, LINbus, MMC/SD/SDIO, QSPI, SmartCard, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, LCD, POR, PWM, WDT
Number of I/O	87
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 16x12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	112-LFBGA
Supplier Device Package	112-BGA (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32gg11b420f2048il112-ar

3. System Overview

3.1 Introduction

The Giant Gecko Series 1 product family is well suited for any battery operated application as well as other systems requiring high performance and low energy consumption. This section gives a short introduction to the MCU system. The detailed functional description can be found in the Giant Gecko Series 1 Reference Manual.

A block diagram of the Giant Gecko Series 1 family is shown in Figure 3.1 Detailed EFM32GG11 Block Diagram on page 11. The diagram shows a superset of features available on the family, which vary by OPN. For more information about specific device features, consult Ordering Information.

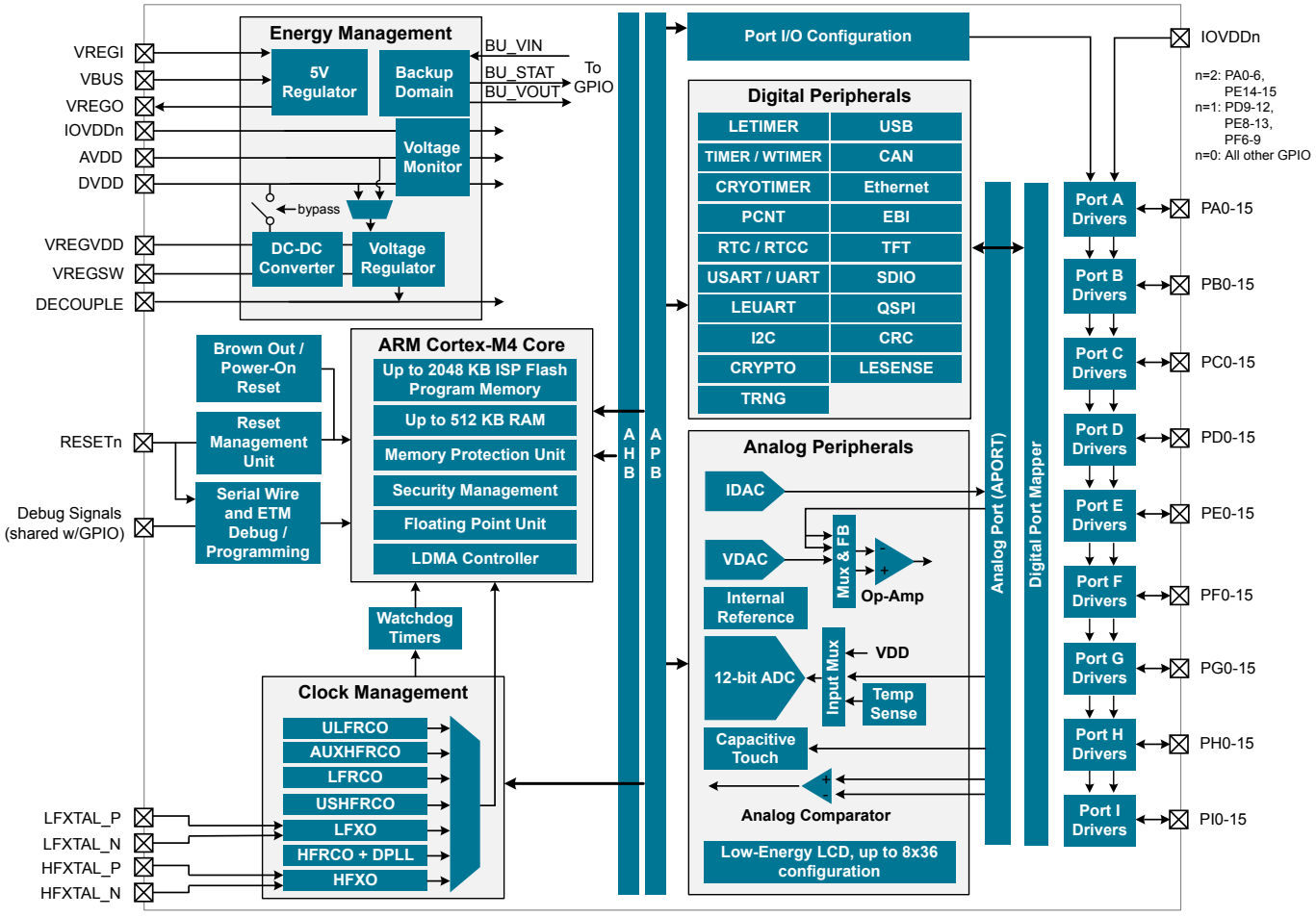

Figure 3.1. Detailed EFM32GG11 Block Diagram

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the following conditions, unless stated otherwise:

- Typical values are based on T_{AMB}=25 °C and V_{DD}= 3.3 V, by production test and/or technology characterization.
- Minimum and maximum values represent the worst conditions across supply voltage, process variation, and operating temperature, unless stated otherwise.

Refer to 4.1.2.1 General Operating Conditions for more details about operational supply and temperature limits.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:

1. The minimum voltage required in bypass mode is calculated using R_{BYP} from the DCDC specification table. Requirements for other loads can be calculated as $V_{DVDD\_min}+I_{LOAD} * R_{BYP\_max}$.
2. VREGVDD must be tied to AVDD. Both VREGVDD and AVDD minimum voltages must be satisfied for the part to operate.
3. The system designer should consult the characteristic specs of the capacitor used on DECOUPLE to ensure its capacitance value stays within the specified bounds across temperature and DC bias.
4. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV / usec for approximately 20 usec. During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 µF capacitor) to 70 mA (with a 2.7 µF capacitor).
5. When the CSEN peripheral is used with chopping enabled (CSEN_CTRL_CHOPEN = ENABLE), IOVDD must be equal to AVDD.
6. The maximum limit on T_A may be lower due to device self-heating, which depends on the power dissipation of the specific application. T_A (max) = T_J (max) - ($THETA_{JA}$ x PowerDissipation). Refer to the Absolute Maximum Ratings table and the Thermal Characteristics table for T_J and $THETA_{JA}$.

4.1.3 Thermal Characteristics

Table 4.3. Thermal Characteristics

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal resistance, QFN64 Package	$THETA_{JA\_QFN64}$	4-Layer PCB, Air velocity = 0 m/s	—	17.8	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	15.4	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	13.8	—	°C/W
Thermal resistance, TQFP64 Package	$THETA_{JA\_TQFP64}$	4-Layer PCB, Air velocity = 0 m/s	—	33.9	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	32.1	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	30.1	—	°C/W
Thermal resistance, TQFP100 Package	$THETA_{JA\_TQFP100}$	4-Layer PCB, Air velocity = 0 m/s	—	44.1	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	37.7	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	35.5	—	°C/W
Thermal resistance, BGA112 Package	$THETA_{JA\_BGA112}$	4-Layer PCB, Air velocity = 0 m/s	—	42.0	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	37.0	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	35.3	—	°C/W
Thermal resistance, BGA120 Package	$THETA_{JA\_BGA120}$	4-Layer PCB, Air velocity = 0 m/s	—	47.9	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	41.8	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	39.6	—	°C/W
Thermal resistance, BGA152 Package	$THETA_{JA\_BGA152}$	4-Layer PCB, Air velocity = 0 m/s	—	35.7	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	31.0	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	29.5	—	°C/W
Thermal resistance, BGA192 Package	$THETA_{JA\_BGA192}$	4-Layer PCB, Air velocity = 0 m/s	—	47.9	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	41.8	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	39.6	—	°C/W

4.1.4 DC-DC Converter

Test conditions: L_DCDC=4.7 µH (Murata LQH3NPN4R7MM0L), C_DCDC=4.7 µF (Samsung CL10B475KQ8NQNC), V_DCDC_I=3.3 V, V_DCDC_O=1.8 V, I_DCDC_LOAD=50 mA, Heavy Drive configuration, F_DCDC_LN=7 MHz, unless otherwise indicated.

Table 4.4. DC-DC Converter

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input voltage range	V_{DCDC_I}	Bypass mode, I_{DCDC_LOAD} = 50 mA	1.8	—	$V_{VREGVDD\_MAX}$	V
		Low noise (LN) mode, 1.8 V output, I_{DCDC_LOAD} = 100 mA, or Low power (LP) mode, 1.8 V output, I_{DCDC_LOAD} = 10 mA	2.4	—	$V_{VREGVDD\_MAX}$	V
		Low noise (LN) mode, 1.8 V output, I_{DCDC_LOAD} = 200 mA	2.6	—	$V_{VREGVDD\_MAX}$	V
Output voltage programmable range[1]	V_{DCDC_O}		1.8	—	$V_{VREGVDD}$	V
Regulation DC accuracy	ACC_{DC}	Low Noise (LN) mode, 1.8 V target output	TBD	—	TBD	V
Regulation window[4]	WIN_{REG}	Low Power (LP) mode, LPCMPBIASEMxx[3] = 0, 1.8 V target output, I_{DCDC_LOAD} ≤ 75 µA	TBD	—	TBD	V
		Low Power (LP) mode, LPCMPBIASEMxx[3] = 3, 1.8 V target output, I_{DCDC_LOAD} ≤ 10 mA	TBD	—	TBD	V
Steady-state output ripple	V_R		—	3	—	mVpp
Output voltage under/overshoot	V_{OV}	CCM Mode (LNFORCECCM[3] = 1), Load changes between 0 mA and 100 mA	—	25	TBD	mV
		DCM Mode (LNFORCECCM[3] = 0), Load changes between 0 mA and 10 mA	—	45	TBD	mV
		Overshoot during LP to LN CCM/DCM mode transitions compared to DC level in LN mode	—	200	—	mV
		Undershoot during BYP/LP to LN CCM (LNFORCECCM[3] = 1) mode transitions compared to DC level in LN mode	—	40	—	mV
		Undershoot during BYP/LP to LN DCM (LNFORCECCM[3] = 0) mode transitions compared to DC level in LN mode	—	100	—	mV
DC line regulation	V_{REG}	Input changes between $V_{VREGVDD\_MAX}$ and 2.4 V	—	0.1	—	%
DC load regulation	I_{REG}	Load changes between 0 mA and 100 mA in CCM mode	—	0.1	—	%

4.1.8 Wake Up Times

Table 4.10. Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Wake up time from EM1	t_{EM1_WU}		—	3	—	AHB Clocks
Wake up from EM2	t_{EM2_WU}	Code execution from flash	—	11.8	—	µs
		Code execution from RAM	—	4.1	—	µs
Wake up from EM3	t_{EM3_WU}	Code execution from flash	—	11.8	—	µs
		Code execution from RAM	—	4.1	—	µs
Wake up from EM4H[1]	t_{EM4H_WU}	Executing from flash	—	94	—	µs
Wake up from EM4S[1]	t_{EM4S_WU}	Executing from flash	—	294	—	µs
Time from release of reset source to first instruction execution	t_{RESET}	Soft Pin Reset released	—	55	—	µs
		Any other reset released	—	359	—	µs
Power mode scaling time	t_{SCALE}	VSCALE0 to VSCALE2, HFCLK = 19 MHz[4] [2]	—	31.8	—	µs
		VSCALE2 to VSCALE0, HFCLK = 19 MHz[3]	—	4.3	—	µs

Note:

1. Time from wake up request until first instruction is executed. Wakeup results in device reset.
2. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV/µs for approximately 20 µs. During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 µF capacitor) to 70 mA (with a 2.7 µF capacitor).
3. Scaling down from VSCALE2 to VSCALE0 requires approximately 2.8 µs + 29 HFCLKs.
4. Scaling up from VSCALE0 to VSCALE2 requires approximately 30.3 µs + 28 HFCLKs.

4.1.10.6 USB High-Frequency RC Oscillator (USHFRCO)

Table 4.17. USB High-Frequency RC Oscillator (USHFRCO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Frequency accuracy	$f_{USHFRCO\_ACC}$	At production calibrated frequencies, across supply voltage and temperature	TBD	—	TBD	%
		USB clock recovery enabled, Active connection as device, FINETUNINGEN[1] = 1	-0.25	—	0.25	%
Start-up time	$t_{USHFRCO}$		—	300	—	ns
Current consumption on all supplies	$I_{USHFRCO}$	$f_{USHFRCO}$ = 48 MHz, FINETUNINGEN[1] = 1	—	340	TBD	µA
		$f_{USHFRCO}$ = 50 MHz, FINETUNINGEN[1] = 0	—	342	TBD	µA
		$f_{USHFRCO}$ = 48 MHz, FINETUNINGEN[1] = 0	—	292	TBD	µA
		$f_{USHFRCO}$ = 32 MHz, FINETUNINGEN[1] = 0	—	223	TBD	µA
		$f_{USHFRCO}$ = 16 MHz, FINETUNINGEN[1] = 0	—	132	TBD	µA
Period jitter	$PJ_{USHFRCO}$		—	0.2	—	% RMS

Note:
1. In the CMU_USHFRCOCTRL register.

4.1.10.7 Ultra-low Frequency RC Oscillator (ULFRCO)

Table 4.18. Ultra-low Frequency RC Oscillator (ULFRCO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Oscillation frequency	f_{ULFRCO}		TBD	1	TBD	kHz

4.1.17 Current Digital to Analog Converter (IDAC)

Table 4.25. Current Digital to Analog Converter (IDAC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Number of ranges	N_{IDAC_RANGES}		—	4	—	ranges
Output current	I_{IDAC_OUT}	RANGSEL[1] = RANGE0	0.05	—	1.6	µA
		RANGSEL[1] = RANGE1	1.6	—	4.7	µA
		RANGSEL[1] = RANGE2	0.5	—	16	µA
		RANGSEL[1] = RANGE3	2	—	64	µA
Linear steps within each range	N_{IDAC_STEPS}		—	32	—	steps
Step size	SS_{IDAC}	RANGSEL[1] = RANGE0	—	50	—	nA
		RANGSEL[1] = RANGE1	—	100	—	nA
		RANGSEL[1] = RANGE2	—	500	—	nA
		RANGSEL[1] = RANGE3	—	2	—	µA
Total accuracy, STEPSEL[1] = 0x10	ACC_{IDAC}	EM0 or EM1, AVDD=3.3 V, T = 25 °C	TBD	—	TBD	%
		EM0 or EM1, Across operating temperature range	TBD	—	TBD	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-2.7	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-2.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-1.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-1.0	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%
		EM2 or EM3, Sink mode, RANGSEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%

4.1.25 External Bus Interface (EBI)

EBI Write Enable Output Timing

Timing applies to both EBI_WEn and EBI_NANDWEn for all addressing modes and both polarities. All numbers are based on route locations 0,1,2 only (with all EBI alternate functions using the same location at the same time). Timing is specified at 10% and 90% of IOVDD, 25 pF external loading, and slew rate for all GPIO set to 6.

Table 4.36. EBI Write Enable Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output hold time, from trailing EBI_WEn / EBI_NANDWEn edge to EBI_AD, EBI_A, EBI_CSn, EBI_BLn invalid	t_{OH_WEn}	IOVDD ≥ 1.62 V	-22 + (WRHOLD * $t_{\{HFCORECLK\}}$)	—	—	ns
		IOVDD ≥ 3.0 V	-13 + (WRHOLD * $t_{HFCORECLK}$)	—	—	ns
Output setup time, from EBI_AD, EBI_A, EBI_CSn, EBI_BLn valid to leading EBI_WEn / EBI_NANDWEn edge[1]	t_{OSU_WEn}	IOVDD ≥ 1.62 V	-12 + (WRSETUP * $t_{HFCORECLK}$)	—	—	ns
		IOVDD ≥ 3.0 V	-10 + (WRSETUP * $t_{HFCORECLK}$)	—	—	ns
EBI_WEn / EBI_NANDWEn pulse width[1]	t_{WIDTH_WEn}	IOVDD ≥ 1.62 V	-6 + (MAX(1, WRSTRB) * $t_{HFCORECLK}$)	—	—	ns
		IOVDD ≥ 3.0 V	-5 + (MAX(1, WRSTRB) * $t_{HFCORECLK}$)	—	—	ns

Note:

1. The figure shows the timing for the case that the half strobe length functionality is not used, i.e. HALFWE=0. The leading edge of EBI_WEn can be moved to the right by setting HALFWE=1. This decreases the length of t_{WIDTH_WEn} and increases the length of t_{OSU_WEn} by 1/2 * $t_{HFCLKNODIV}$.

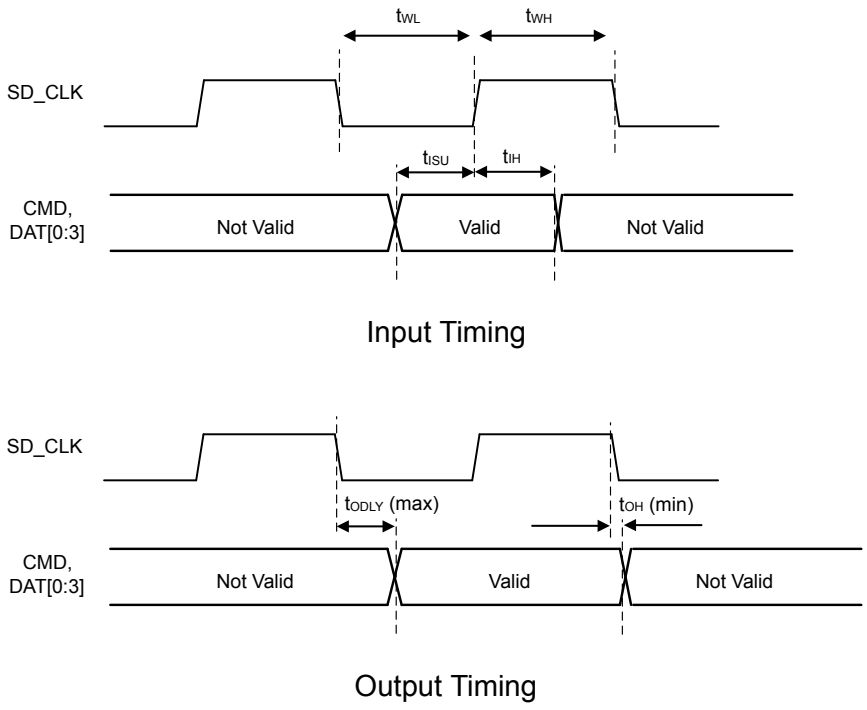

Figure 4.13. SDIO DS Mode Timing

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
IOVDD1	F7 G7	Digital IO power supply 1.	VSS	F8 G8 G9 H6 H7 H8 H9 H10 H11 J6 J7 J8 J9 J10 J11 K8 K9 L8 L9	Ground
NC	F9	No Connect.	IOVDD0	F10 F11 G10 G11 K6 K7 K10 K11 L6 L7 L10 L11	Digital IO power supply 0.
PI5	F14	GPIO (5V)	PI4	F15	GPIO (5V)
PI3	F16	GPIO (5V)	PA5	G1	GPIO
PG6	G2	GPIO (5V)	PG5	G3	GPIO (5V)
PI2	G14	GPIO (5V)	PI1	G15	GPIO (5V)
PI0	G16	GPIO (5V)	PA6	H1	GPIO
PG8	H2	GPIO (5V)	PG7	H3	GPIO (5V)
PE5	H14	GPIO	PE6	H15	GPIO
PE7	H16	GPIO	PG11	J1	GPIO (5V)
PG10	J2	GPIO (5V)	PG9	J3	GPIO (5V)
PE3	J14	GPIO	PE4	J15	GPIO
DECOUPLE	J16	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PG14	K1	GPIO
PG13	K2	GPIO	PG12	K3	GPIO
PE1	K14	GPIO (5V)	PE2	K15	GPIO
DVDD	K16	Digital power supply.	PG15	L1	GPIO (5V)
PB15	L2	GPIO (5V)	PB0	L3	GPIO
PE0	L14	GPIO (5V)	PC7	L15	GPIO
VREGVDD	L16	Voltage regulator VDD input	PB1	M1	GPIO

5.8 EFM32GG11B8xx in QFP100 Device Pinout

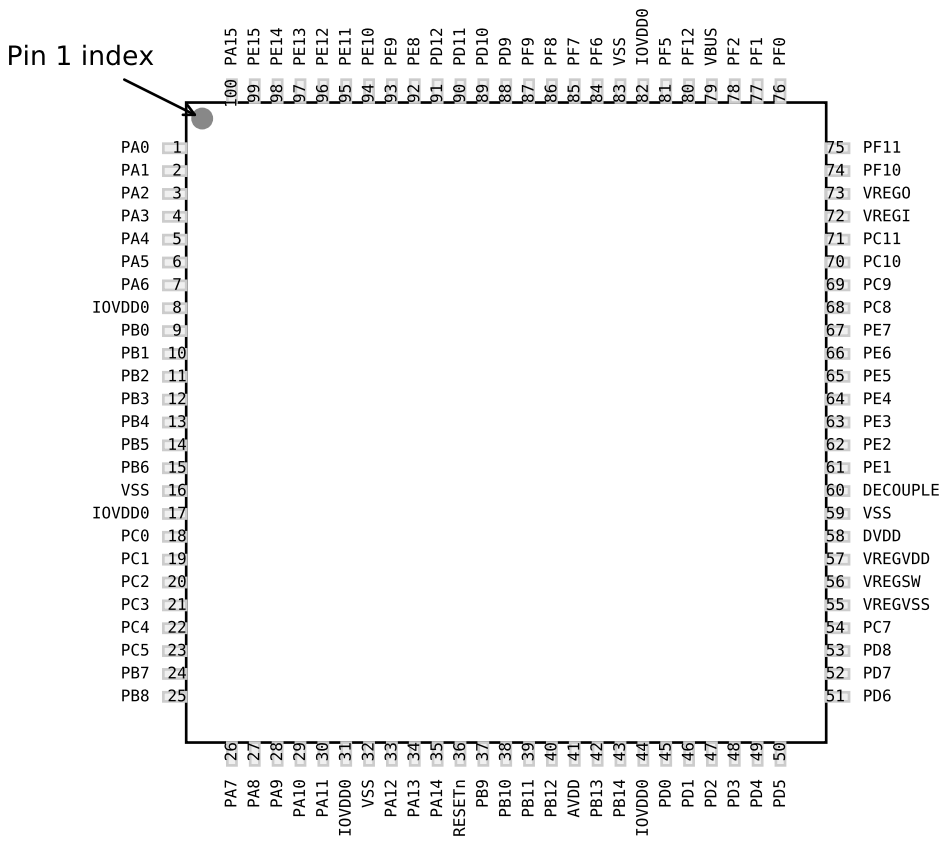

Figure 5.8. EFM32GG11B8xx in QFP100 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see 5.20 GPIO Functionality Table or 5.21 Alternate Functionality Overview.

Table 5.8. EFM32GG11B8xx in QFP100 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PA0	1	GPIO	PA1	2	GPIO
PA2	3	GPIO	PA3	4	GPIO
PA4	5	GPIO	PA5	6	GPIO
PA6	7	GPIO	IOVDD0	8 17 31 44 82	Digital IO power supply 0.
PB0	9	GPIO	PB1	10	GPIO

5.19 EFM32GG11B1xx in QFN64 Device Pinout

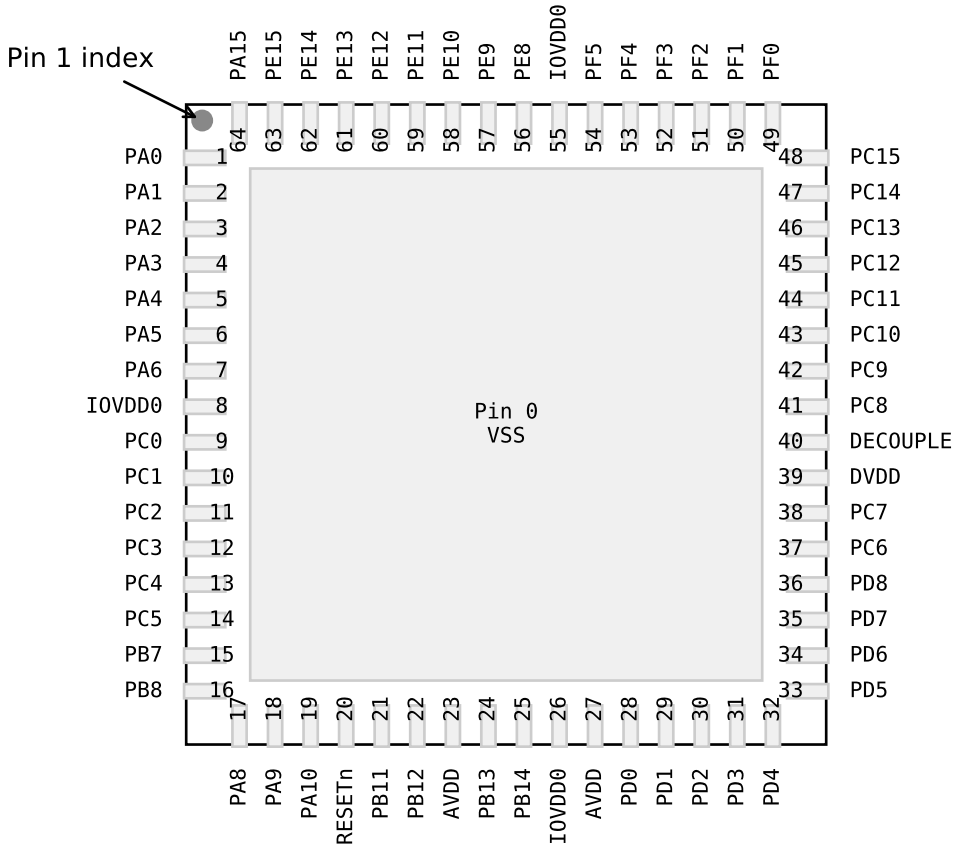

Figure 5.19. EFM32GG11B1xx in QFN64 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see 5.20 GPIO Functionality Table or 5.21 Alternate Functionality Overview.

Table 5.19. EFM32GG11B1xx in QFN64 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VSS	0	Ground	PA0	1	GPIO
PA1	2	GPIO	PA2	3	GPIO
PA3	4	GPIO	PA4	5	GPIO
PA5	6	GPIO	PA6	7	GPIO
IOVDD0	8 26 55	Digital IO power supply 0.	PC0	9	GPIO (5V)
PC1	10	GPIO (5V)	PC2	11	GPIO (5V)

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
PRS_CH7	0: PB13 1: PA7 2: PE7		Peripheral Reflex System PRS, channel 7.
PRS_CH8	0: PA8 1: PA2 2: PE9		Peripheral Reflex System PRS, channel 8.
PRS_CH9	0: PA9 1: PA3 2: PB10		Peripheral Reflex System PRS, channel 9.
PRS_CH10	0: PA10 1: PC2 2: PD4		Peripheral Reflex System PRS, channel 10.
PRS_CH11	0: PA11 1: PC3 2: PD5		Peripheral Reflex System PRS, channel 11.
PRS_CH12	0: PA12 1: PB6 2: PD8		Peripheral Reflex System PRS, channel 12.
PRS_CH13	0: PA13 1: PB9 2: PE14		Peripheral Reflex System PRS, channel 13.
PRS_CH14	0: PA14 1: PC6 2: PE15		Peripheral Reflex System PRS, channel 14.
PRS_CH15	0: PA15 1: PC7 2: PF0		Peripheral Reflex System PRS, channel 15.
PRS_CH16	0: PA4 1: PB12 2: PE4		Peripheral Reflex System PRS, channel 16.
PRS_CH17	0: PA5 1: PB15 2: PE5		Peripheral Reflex System PRS, channel 17.
PRS_CH18	0: PB2 1: PC10 2: PC4		Peripheral Reflex System PRS, channel 18.
PRS_CH19	0: PB3 1: PC11 2: PC5		Peripheral Reflex System PRS, channel 19.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
PRS_CH20	0: PB4 1: PC12 2: PE2		Peripheral Reflex System PRS, channel 20.
PRS_CH21	0: PB5 1: PC13 2: PB11		Peripheral Reflex System PRS, channel 21.
PRS_CH22	0: PB7 1: PE0 2: PF6		Peripheral Reflex System PRS, channel 22.
PRS_CH23	0: PB8 1: PE1 2: PF7		Peripheral Reflex System PRS, channel 23.
QSPI0_CS0	0: PF7 1: PA0 2: PG9		Quad SPI 0 Chip Select 0.
QSPI0_CS1	0: PF8 1: PA1 2: PG10		Quad SPI 0 Chip Select 1.
QSPI0_DQ0	0: PD9 1: PA2 2: PG1		Quad SPI 0 Data 0.
QSPI0_DQ1	0: PD10 1: PA3 2: PG2		Quad SPI 0 Data 1.
QSPI0_DQ2	0: PD11 1: PA4 2: PG3		Quad SPI 0 Data 2.
QSPI0_DQ3	0: PD12 1: PA5 2: PG4		Quad SPI 0 Data 3.
QSPI0_DQ4	0: PE8 1: PB3 2: PG5		Quad SPI 0 Data 4.
QSPI0_DQ5	0: PE9 1: PB4 2: PG6		Quad SPI 0 Data 5.
QSPI0_DQ6	0: PE10 1: PB5 2: PG7		Quad SPI 0 Data 6.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
TIM4_CDTI2	0: PD3		Timer 4 Complimentary Dead Time Insertion channel 2.
TIM5_CC0	0: PE4 1: PE7 2: PH13 3: PI0	4: PC8 5: PC11 6: PC14 7: PF12	Timer 5 Capture Compare input / output channel 0.
TIM5_CC1	0: PE5 1: PH11 2: PH14 3: PI1	4: PC9 5: PC12 6: PF10 7: PF13	Timer 5 Capture Compare input / output channel 1.
TIM5_CC2	0: PE6 1: PH12 2: PH15 3: PI2	4: PC10 5: PC13 6: PF11 7: PF14	Timer 5 Capture Compare input / output channel 2.
TIM6_CC0	0: PG0 1: PG6 2: PG12 3: PH2	4: PH8 5: PB13 6: PD1 7: PD4	Timer 6 Capture Compare input / output channel 0.
TIM6_CC1	0: PG1 1: PG7 2: PG13 3: PH3	4: PH9 5: PB14 6: PD2 7: PD5	Timer 6 Capture Compare input / output channel 1.
TIM6_CC2	0: PG2 1: PG8 2: PG14 3: PH4	4: PH10 5: PD0 6: PD3 7: PD6	Timer 6 Capture Compare input / output channel 2.
TIM6_CDTI0	0: PG3 1: PG9 2: PE4 3: PH5		Timer 6 Complimentary Dead Time Insertion channel 0.
TIM6_CDTI1	0: PG4 1: PG10 2: PE5 3: PH6		Timer 6 Complimentary Dead Time Insertion channel 1.
TIM6_CDTI2	0: PG5 1: PG11 2: PE6 3: PH7		Timer 6 Complimentary Dead Time Insertion channel 2.
U0_CTS	0: PF8 1: PE2 2: PA5 3: PC13	4: PB7 5: PD5	UART0 Clear To Send hardware flow control input.
U0_RTS	0: PF9 1: PE3 2: PA6 3: PC12	4: PB8 5: PD6	UART0 Request To Send hardware flow control output.
U0_RX	0: PF7 1: PE1 2: PA4 3: PC15	4: PC5 5: PF2 6: PE4	UART0 Receive input.

Table 5.25. ACMP2 Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
APORT0X	BUSACMP2X																									PG7	PG6	PG5	PG4	PG3	PG2	PG1	PG0
APORT0Y	BUSACMP2Y																									PG7	PG6	PG5	PG4	PG3	PG2	PG1	PG0
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0

Table 5.31. VDAC0 / OPA Bus and Pin Mapping

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
OPA0_N																																	
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
OPA0_P																																	
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	

Port	Bus	CH31	CH30	CH29	CH28	CH27	CH26	CH25	CH24	CH23	CH22	CH21	CH20	CH19	CH18	CH17	CH16	CH15	CH14	CH13	CH12	CH11	CH10	CH9	CH8	CH7	CH6	CH5	CH4	CH3	CH2	CH1	CH0
OPA3_OUT																																	
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
OPA3_P																																	
APORT1X	BUSAX		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT2X	BUSBX	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT3X	BUSCX		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0
APORT4X	BUSDX	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
VDAC0_OUT0 / OPA0_OUT																																	
APORT1Y	BUSAY	PB15		PB13		PB11		PB9				PB5		PB3		PB1		PA15		PA13		PA11		PA9		PA7		PA5		PA3		PA1	
APORT2Y	BUSBY		PB14		PB12		PB10				PB6		PB4		PB2		PB0		PA14		PA12		PA10		PA8		PA6		PA4		PA2		PA0
APORT3Y	BUSCY	PF15		PF13		PF11		PF9		PF7		PF5		PF3		PF1		PE15		PE13		PE11		PE9		PE7		PE5				PE1	
APORT4Y	BUSDY		PF14		PF12		PF10		PF8		PF6		PF4		PF2		PF0		PE14		PE12		PE10		PE8		PE6		PE4				PE0

10. TQFP100 Package Specifications

10.1 TQFP100 Package Dimensions

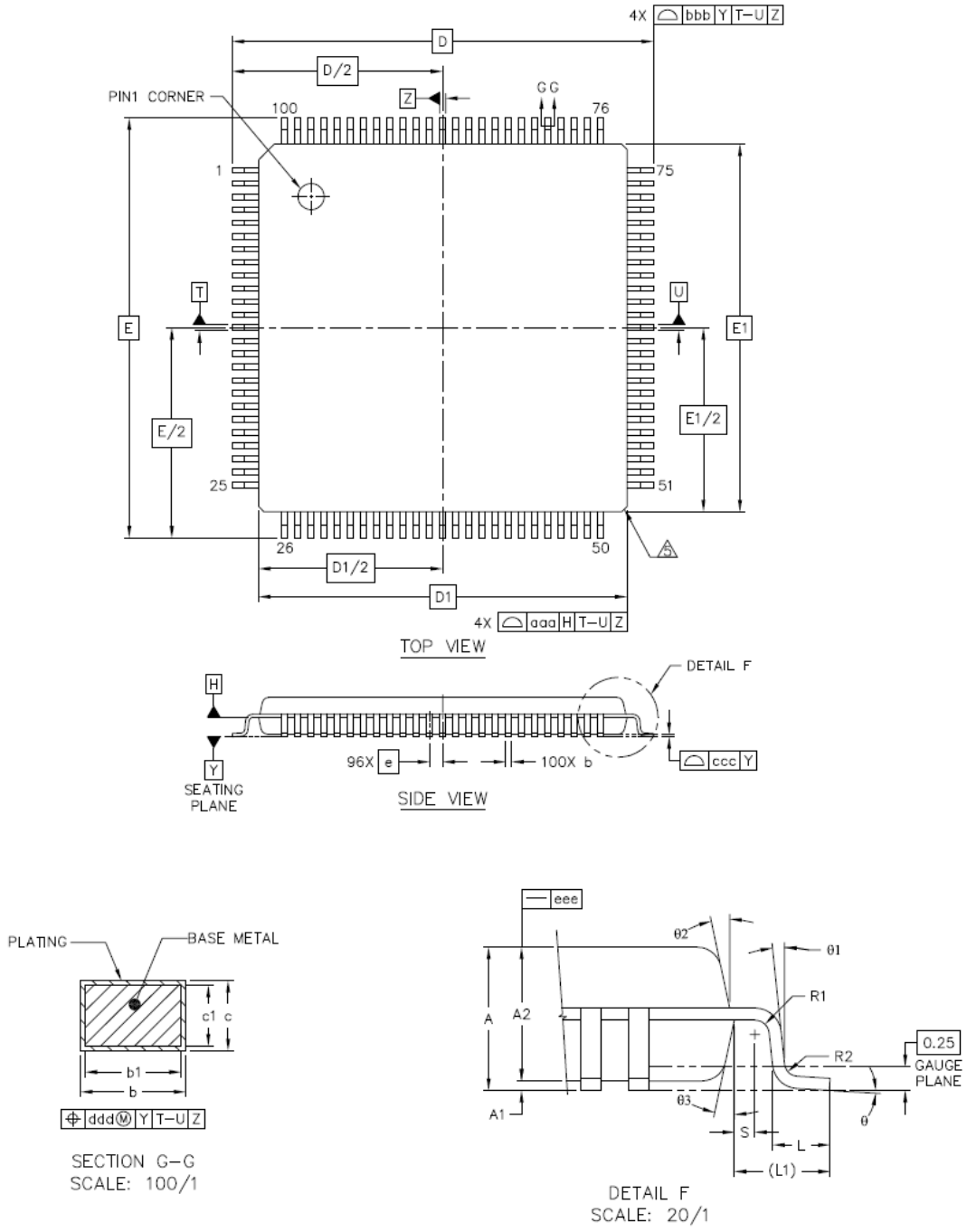

Figure 10.1. TQFP100 Package Drawing

13. Revision History

Revision 0.6

March, 2018

- Removed "Confindential" watermark.
- Updated 4.1 Electrical Characteristics and 4.2 Typical Performance Curves with latest characterization data.

Revision 0.2

October, 2017

- Updated memory maps to latest formatting and to include all peripherals.
- Updated all electrical specifications tables with latest characterization results.
- **Absolute Maximum Ratings** Table:
  - Removed redundant I_{VSSMAX} line.
  - Added footnote to clarify V_{DIGPIN} specification for 5V tolerant GPIO.
- **General Operating Conditions** Table:
  - Removed dV_{DD} specification and redundant footnote about shorting VREGVDD and AVDD together.
  - Added footnote about IOVDD voltage restriction when CSEN peripheral is used with chopping enabled.
- **Flash Memory Characteristics** Table: Added timing measurement clarification for Device Erase and Mass Erase.
- **Analog to Digital Converter (ADC)** Table:
  - Added header text for general specification conditions.
  - Added footnote for clarification of input voltage limits.
- Minor typographical corrections, including capitalization, mis-spellings and punctuation marks, throughout document.
- Minor formatting and styling updates, including table formats, TOC location, and boilerplate information throughout document.

Revision 0.1

April 27th, 2017

Initial release.